

<b>Notice of References Cited</b>	Application/Control No. 10/522,043	Applicant(s)/Patent Under Reexamination LU ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Stiewe et al (JBC, 4/19/02, 277(16): 14177-14185)
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